



Structured data analytics and automated dashboards for rapid assessment and drill down into manufacturing priorities

Fast Prioritization of Product Yield Limiters

The Guided Analytics sub-module is an option to enhance Exensio™ Manufacturing Analytics and Exensio™ Test Operations. It provides an easy to use interface with a high-level dashboard for fast assessment across multiple products. Guided Analytics provides prioritization of yield and test issues, identification of important patterns and trends, and AI/ML driven automated root cause analysis for yield failures while continuously mining the data collected across your global supply chain. The pre-configured analysis framework guides the user through an issue based analysis path for your fabless manufacturing environment, helping you focus on what is truly important to maintain your products yield and bring them to market quickly and profitably.

Visualization for Executives and Engineers

Guided Analytics removes information bottlenecks and enables a consistent approach to tracking your key performance indicators (KPIs) and serves a diverse user community. Each dashboard is configurable to the needs of the viewer. From an executive who wants to be sure that their supply chain will provide enough good die to fulfill their customer obligations, to the product engineer who is tasked with achieving a sub 1 PPM failure rate, Guided Analytics provides the right information for every user.

All product data is fully managed by the Manufacturing Analytics module, enabling Guided Analytics to provide rapid signature identification for all KPIs such as yield to target, wafer spatial patterns, and test equipment trends, and guides the users through a corresponding analysis path. In addition, with the seamless connection to Manufacturing Analytics, users can also perform deeper ad hoc root cause analysis.

Module Highlights

- **Intuitive dashboard for fast assessment and prioritization of manufacturing and test issues**
- **Quickly guide users to identify key data signals using hierarchical framework**
- **AI/ML module automates root cause analysis for yield failures**
- **Support for multiple data types (PCM/WAT, WS & FT Hard/Soft Bins, Retest, Parametric test, Test equipment, etc.)**
- **Fully integrated to the Exensio™ Manufacturing Analytics Module for deep drill downs**
- **Shared links for fast communications to your entire team with support for desktops, laptops, tablets, and smartphones**

GUIDED ANALYTICS

Quickly and seamlessly visualize all your data

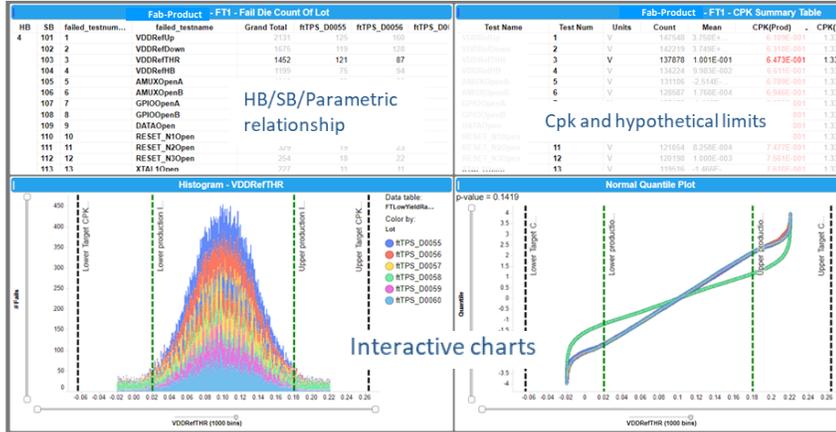


Figure 1: Link Hard Bin to Soft Bin to Parametric Test Data. Calculate CPK with actual and hypothetical limits. Interactive charts.

Module Prerequisites

- Manufacturing Analytics Module
- Test Operations Module
- Big Data Module
- Automation & Reporting Module

For more information about these modules or solutions, contact your local sales representative or visit pdf.com

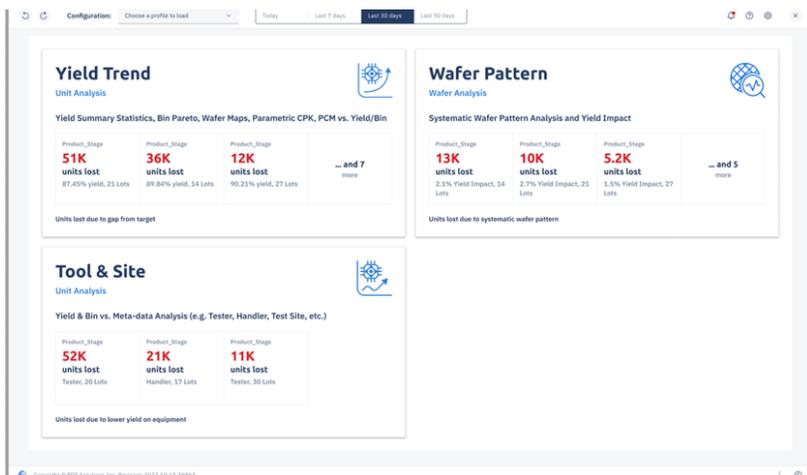


Figure 2: User-configurable dashboard. "Units lost" metric guides user to prioritize which area of analysis to investigate.

Exensio visualizations Powered by Spotfire®

Prioritize Your Virtual Team's Workload

Knowing what issues need to be addressed is important, and so is aligning your entire team and supply chain to solving the task at hand. Guided Analytics enables immediate notification of issues via links that can be viewed by anyone you wish. With the Guided Analytics sub-module, every dashboard is connected to the same fully integrated database. Everyone is looking at the same data no matter where they are, and the platform provides a standardized analysis flow across organizations. Enable your team with a single point of truth for every issue they investigate.

More Information

For customers with additional questions about Guided Analysis or any other PDF Solutions products or services, contact us at info@pdf.com.

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